FAIRCHILD SEMICONDUCTOR™

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74F652
Transceivers/Registers

General Description

These devices consist of bus transceiver circuits with D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the input bus or from internal registers. Data on the A or B bus will be clocked into the registers as the appropriate clock pin goes to HIGH logic level. Output Enable pins (OEAB, $\overline{OEBA}$) are provided to control the transceiver function.

Features

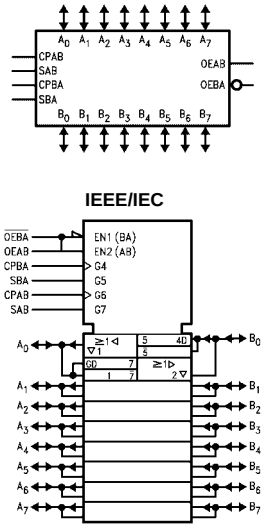
- Independent registers for A and B buses
- Multiplexed real-time and stored data
- 74F652 non-inverting data path

Ordering Code:

Order Number	Package Number	Package Description
74F652SC (Note 1)	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
74F652SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

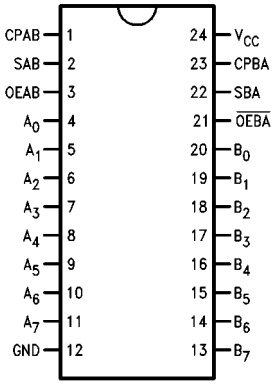
Note 1: Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols



IEEE/IEC

Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L. HIGH/LOW	Input I_{IH}/I_{IL} Output I_{OH}/I_{OL}
A_0–A_7, B_0–B_7	A and B Inputs/	1.0/1.0	20 µA/–0.6 mA
	3-STATE Outputs	600/106.6 (80)	–12 mA/64 mA (48 mA)
CPAB, CPBA	Clock Inputs	1.0/1.0	20 µA/–0.6 mA
SAB, SBA	Select Inputs	1.0/1.0	20 µA/–0.6 mA
OEAB, $\overline{\text{OEBA}}$	Output Enable Inputs	1.0/1.0	20 µA/–0.6 mA

Function Table

Inputs						Inputs/Outputs (Note 2)		Operating Mode
OEAB	$\overline{\text{OEBA}}$	CPAB	CPBA	SAB	SBA	A_0 thru A_7	B_0 thru B_7	
L	H	H or L	H or L	X	X	Input	Input	Isolation
L	H	⌐	⌐	X	X			Store A and B Data
X	H	⌐	H or L	X	X	Input	Not Specified	Store A, Hold B
H	H	⌐	⌐	X	X	Input	Output	Store A in Both Registers
L	X	H or L	⌐	X	X	Not Specified	Input	Hold A, Store B
L	L	⌐	⌐	X	X	Output	Input	Store B in Both Registers
L	L	X	X	X	L	Output	Input	Real-Time B Data to A Bus
L	L	X	H or L	X	H			Store B Data to A Bus
H	H	X	X	L	X	Input	Output	Real-Time A Data to B Bus
H	H	H or L	X	H	X			Stored A Data to B Bus
H	L	H or L	H or L	H	H	Output	Output	Stored A Data to B Bus and Stored B Data to A Bus

H = HIGH Voltage Level X = Immaterial
L = LOW Voltage Level ⌐ = LOW-to-HIGH Clock Transition

Note 2: The data output functions may be enabled or disabled by various signals at OEAB or OEBA inputs. Data input functions are always enabled, i.e., data at the bus pins will be stored on every LOW-to-HIGH transition on the clock inputs.

Functional Description

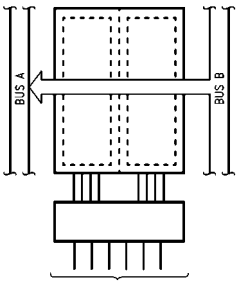
In the transceiver mode, data present at the HIGH impedance port may be stored in either the A or B register or both.

The select (SAB, SBA) controls can multiplex stored and real-time.

The examples in Figure 1 demonstrate the four fundamental bus-management functions that can be performed with the Octal bus transceivers and receivers.

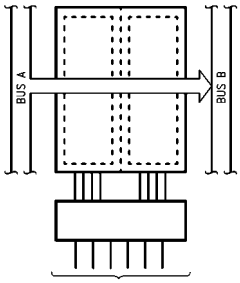
Data on the A or B data bus, or both can be stored in the internal D flip-flop by LOW-to-HIGH transitions at the appropriate Clock Inputs (CPAB, CPBA) regardless of the Select or Output Enable Inputs. When SAB and SBA are in the real time transfer mode, it is also possible to store data without using the internal D flip-flops by simultaneously enabling OEAB and OEBA. In this configuration each Output reinforces its Input. Thus when all other data sources to the two sets of bus lines are in a HIGH impedance state, each set of bus lines will remain at its last state.

Note A: Real-Time Transfer Bus B to Bus A



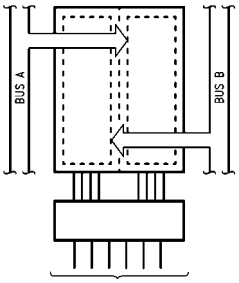
OEAB	$\overline{OEBA}$	CPAB	CPBA	SAB	SBA
L	L	X	X	X	L

Note B: Real-Time Transfer Bus A to Bus B



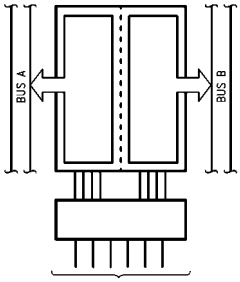
OEAB	$\overline{OEBA}$	CPAB	CPBA	SAB	SBA
H	H	X	X	L	X

Note C: Storage



OEAB	$\overline{OEBA}$	CPAB	CPBA	SAB	SBA
X	H	↓	X	X	X
L	X	X	↓	X	X
L	H	↓	↓	X	X

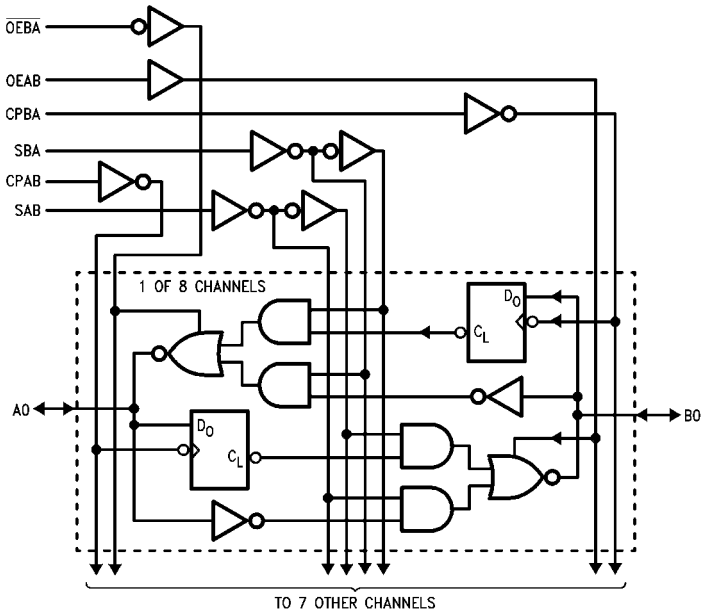
Note D: Transfer Storage Data to A or B



OEAB	$\overline{OEBA}$	CPAB	CPBA	SAB	SBA
H	L	H or L	H or L	H	X

FIGURE 1.

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 3)

Storage Temperature	−65°C to +150°C
Ambient Temperature under Bias	−55°C to +125°C
Junction Temperature under Bias	−55°C to +150°C
V_{CC} Pin Potential to Ground Pin	−0.5V to +7.0V
Input Voltage (Note 4)	−0.5V to +7.0V
Input Current (Note 4)	−30 mA to +5.0 mA
Voltage Applied to Output	
in HIGH State (with V_{CC} = 0V)	
Standard Output	−0.5V to V_{CC}
3-STATE Output	−0.5V to +5.5V
Current Applied to Output	
in LOW State (Max)	twice the rated I_{OL} (mA)
ESD Last Passing Voltage (Min)	4000V

Recommended Operating Conditions

Free Air Ambient Temperature	0°C to +70°C
Supply Voltage	+4.5V to +5.5V

Note 3: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 4: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Parameter	Min	Typ	Max	Units	V_{CC}	Conditions
V_{IH}	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal
V_{IL}	Input LOW Voltage			0.8	V		Recognized as a LOW Signal
V_{CD}	Input Clamp Diode Voltage			−1.2	V	Min	I_{IN} = −18 mA (Non I/O Pins)
V_{OH}	Output HIGH Voltage 10% V_{CC}	2.0			V	Min	I_{OH} = −15 mA (A_n, B_n)
V_{OL}	Output LOW Voltage 10% V_{CC}			0.55	V	Min	I_{OL} = 64 mA (A_n, B_n)
I_{IH}	Input HIGH Current			5.0	µA	Max	V_{IN} = 2.7V (Non I/O Pins)
I_{BVI}	Input HIGH Current Breakdown Test			7.0	µA	Max	V_{IN} = 7.0V
I_{BVIT}	Input HIGH Current Breakdown (I/O)			0.5	mA	Max	V_{IN} = 5.5V (A_n, B_n)
I_{CEX}	Output HIGH Leakage Current			50	µA	Max	V_{OUT} = V_{CC}
V_{ID}	Input Leakage Test	4.75			V	0.0	I_{ID} = 1.9 µA All Other Pins Grounded
I_{OD}	Output Leakage Circuit Current			3.75	µA	0.0	VI_{IOD} = 150 mV All Other Pins Grounded
I_{IL}	Input LOW Current			−0.6	mA	Max	V_{IN} = 0.5V (Non I/O Pins)
I_{IH} + I_{OZH}	Output Leakage Current			70	µA	Max	V_{OUT} = 2.7V (A_n, B_n)
I_{IL} + I_{OZL}	Output Leakage Current			−650	µA	Max	V_{OUT} = 0.5V (A_n, B_n)
I_{OS}	Output Short-Circuit Current	−100		−225	mA	Max	V_{OUT} = 0V
I_{ZZ}	Bus Drainage Test			500	µA	0.0V	V_{OUT} = 5.25V
I_{CCH}	Power Supply Current		105	135	mA	Max	V_O = HIGH
I_{CCL}	Power Supply Current		118	150	mA	Max	V_O = LOW
I_{CCZ}	Power Supply Current		115	150	mA	Max	V_O = HIGH Z

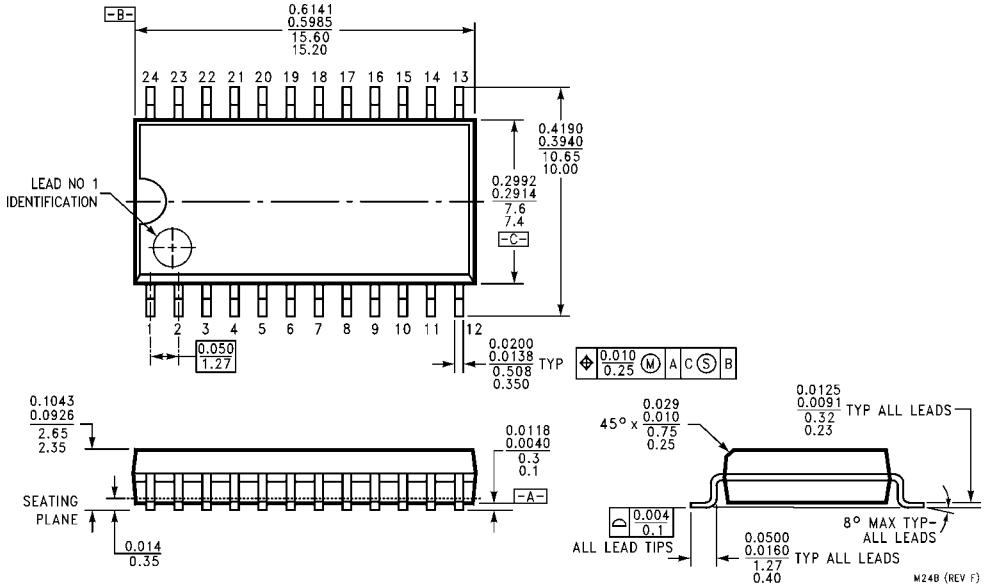
AC Electrical Characteristics

Symbol	Parameter	$T_A = +25°C$, $V_{CC} = +5.0V$, $C_L = 50$ pF		$T_A = -55°C$ to $+125°C$, $V_{CC} = +5.0V$, $C_L = 50$ pF		$T_A = 0°C$ to $+70°C$, $V_{CC} = +5.0V$, $C_L = 50$ pF		Units
		Min	Max	Min	Max	Min	Max	
f_{MAX}	Max. Clock Frequency	90		75		90		MHz
t_{PLH}	Propagation Delay	2.0	7.0	2.0	8.5	2.0	8.0	ns
t_{PHL}	Clock to Bus	2.0	8.0	2.0	9.5	2.0	9.0	
t_{PLH}	Propagation Delay	1.0	7.0	1.0	8.0	1.0	7.5	ns
t_{PHL}	Bus to Bus	1.0	6.5	1.0	8.0	1.0	7.0	
t_{PLH}	Propagation Delay	2.0	8.5	2.0	11.0	2.0	9.5	ns
t_{PHL}	SBA or SAB to A or B	2.0	8.0	2.0	10.0	2.0	9.0	

AC Operating Requirements

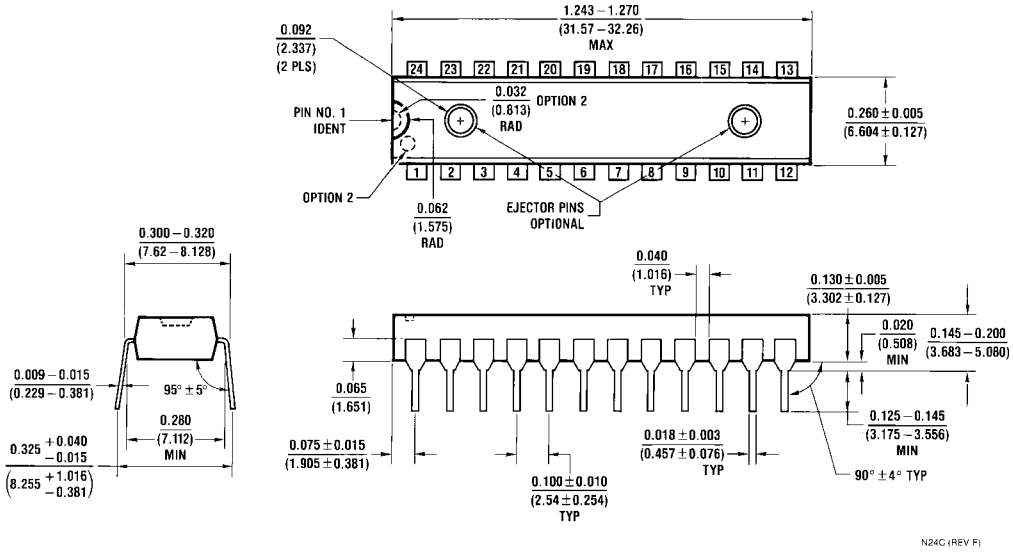
Symbol	Parameter	$T_A = +25°C$, $V_{CC} = +5.0V$		$T_A = -55°C$ to $+125°C$, $V_{CC} = +5.0V$		$T_A = 0°C$ to $+70°C$, $V_{CC} = +5.0V$		Units
		Min	Max	Min	Max	Min	Max	
t_{PZH}	Enable Time	2.0	9.5	2.0	10.0	2.0	10.0	ns
t_{PZL}	*OEBA to A	2.0	12.0	2.0	10.0	2.0	12.5	
t_{PHZ}	Disable Time	1.0	7.5	1.0	9.0	1.0	8.0	
t_{PLZ}	*OEBA to A	2.0	8.5	1.0	9.0	2.0	9.0	
t_{PZH}	Enable Time	2.0	9.5	2.0	10.0	2.0	10.0	
t_{PZL}	OEAB to B	3.0	13.0	2.0	12.0	3.0	14.0	
t_{PHZ}	Disable Time	2.0	9.0	1.0	9.0	2.0	10.0	ns
t_{PLZ}	OEAB to B	2.0	10.5	1.0	12.0	2.0	11.0	
$t_S(H)$	Setup Time, HIGH or	5.0		5.0		5.0		ns
$t_S(L)$	LOW, Bus to Clock	5.0		5.0		5.0		
$t_H(H)$	Hold Time, HIGH or	2.0		2.5		2.0		ns
$t_H(L)$	LOW, Bus to Clock	2.0		2.5		2.0		
$t_W(H)$	Clock Pulse Width	5.0		5.0		5.0		ns
$t_W(L)$	HIGH or LOW	5.0		5.0		5.0		

Physical Dimensions inches (millimeters) unless otherwise noted



24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
Package Number M24B

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide
Package Number N24C